


<b>Issue Classification</b> 	Application No.	Applicant(s)	
	09/302,431	LEE ET AL.	
	Examiner	Art Unit	
	Benjamin E Lanier	2132	

ISSUE CLASSIFICATION									
ORIGINAL		CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
713	193	713	184	156	173	175			
INTERNATIONAL CLASSIFICATION									
H 0 4 C	9 / 06 / 32								
G 0 6 F	11 / 30								
G 0 6 F	12 / 14								
	/								
	/								

Benjamin E. Lanier Jr. 2/16/05 (Assistant Examiner) (Date)	<b>GILBERTO BARRON JR.</b> <b>SUPERVISORY PATENT EXAMINER</b> <b>TECHNOLOGY CENTER 2100</b> (Primary Examiner) (Date)	Total Claims Allowed: 38	
Kim Watson-Grunders 3/31/05 (Legal Instruments Examiner) (Date)		O.G. Print Claim(s) 1	O.G. Print Fig 1

Final		Original		Final		Original		Final		Original		Final		Original		Final		Original	
1	1	29	31	61	91	121	151	181											
2	2	30	32	62	92	122	152	182											
3	3	31	33	63	93	123	153	183											
4	4	32	34	64	94	124	154	184											
5	5	33	35	65	95	125	155	185											
6	6	34	36	66	96	126	156	186											
7	7	35	37	67	97	127	157	187											
8	8	36	38	68	98	128	158	188											
9	9	37	39	69	99	129	159	189											
10	10	38	40	70	100	130	160	190											
11	11	39	41	71	101	131	161	191											
12	12		42	72	102	132	162	192											
13	13		43	73	103	133	163	193											
14	14		44	74	104	134	164	194											
15	15		45	75	105	135	165	195											
16	16		46	76	106	136	166	196											
17	17		47	77	107	137	167	197											
18	18		48	78	108	138	168	198											
19	19		49	79	109	139	169	199											
20	20		50	80	110	140	170	200											
21	21		51	81	111	141	171	201											
22	22		52	82	112	142	172	202											
23	23		53	83	113	143	173	203											
24	24		54	84	114	144	174	204											
25	25		55	85	115	145	175	205											
26	26		56	86	116	146	176	206											
27	27		57	87	117	147	177	207											
28	28		58	88	118	148	178	208											
29	29		59	89	119	149	179	209											
30	30		60	90	120	150	180	210											